



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Adam E. Norton et al.

PATENT APPLICATION

Serial No.: 10/081,078

Group Art Unit: 2877

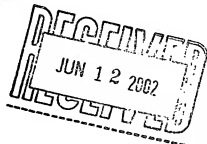
Filed: February 21, 2002

Examiner:

For: SMALL-SPOT SPECTROMETRY INSTRUMENT WITH
REDUCED POLARIZATION AND MULTIPLE-ELEMENT
DEPOLARIZER THEREFOR

Information Disclosure Statement

Hon. Assistant Commissioner
for Patents
Washington, D.C. 20231



Sir:

The following information is submitted in
compliance with Applicants' duty of disclosure under 37
CFR § 1.56. A copy of each reference is enclosed.

<u>Pat. No.</u>	<u>Patentee</u>	<u>Grant Date</u>
4,572,608	Mochizuki et al.	02/25/86
4,922,309	Sekiwa et al.	05/01/90
5,218,652	Lutz	06/08/93
5,371,595	Nishiura et al.	12/06/94
5,430,795	Taga et al.	07/04/95
5,933,555	Shen	08/03/99
6,040,906	Harhay	03/21/00

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Other References

M.E. Lee et al., "Analysis of Reflectometry and
Ellipsometry Data from Patterned Structures", Dept. of
Electrical Engineering and Computer Science, Univ. of
Michigan, MI, 5 pages.

Nasa Research Announcement, "Technical Details
on OMI and Other EOS Chem Instruments", Sept. 29, 1999, 2
pages.

Varian Inc. paper, Scientific Instruments,
"Polarizer and Depolarizer Accessory", June 28, 2000, 2
pages.

CERTIFICATE OF MAILING

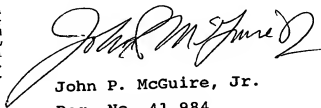
I hereby certify that this paper (along with
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Commissioner for Patents, Washington, D.C.
20231

Signed: Sally Azevedo

Typed Name: Sally Azevedo

Date: May 31, 2002

Respectfully submitted,



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FORM PTO-1449

Atty. Docket No.
SEN-020Serial No.
10/081,078LIST OF PRIOR ART
CITED BY APPLICANTApplicant:
Adam E. Norton et al.Filing Date:
February 21, 2002Group:
2877

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Grant Date	Name	Class	Sub Class	Filing Date
AA	4,572,608	02/25/86	Mochizuki et al.	350	96.15	
AB	4,922,309	05/01/90	Sekiwa et al.	356	300	
AC	5,218,652	06/08/93	Lutz	385	11	
AD	5,371,595	12/06/94	Nishiura et al.	356	350	
AE	5,430,795	07/04/95	Taga et al.	359	179	
AF	5,933,555	08/03/99	Shen	385	32	
AG	6,040,906	03/21/00	Harhay	356	301	
AH						
AI						
AJ						

FOREIGN PATENT DOCUMENTS

Examiner Initial*	Document Number	Grant Date	Country	Class	Sub Class	Translation Yes No
AK						
AL						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	M.E. Lee et al., "Analysis of Reflectometry and Ellipsometry Data from Patterned Structures", Dept. of Electrical Engineering and Computer Science, Univ. of Michigan, MI, 5 pages.
AN	Nasa Research Announcement, "Technical Details on OMI and Other EOS Chem Instruments", Sept. 29, 1999, 2 pages.
AO	Varian Inc. paper, Scientific Instruments, "Polarizer and Depolarizer Accessory", June 28, 2000, 2 pages.

EXAMINER:

DATE CONSIDERED:

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.